REMARKS

Reconsideration of the above-referenced application in view of the following remarks is respectfully requested.

Claims 1-20 were pending in this application. No claims are amended herein.

Claims 1-20 stand rejected under 35 U.S.C. 102(e) as being anticipated by Maeng (U.S. Patent No. 6,313,652). Applicant respectfully traverses the rejection. Claim 1 includes the feature of "a single handler coupled to the first and second testers." The Examiner refers to element 45 in combination with element 21 in Maeng as the claimed "single handler". However, Maeng refers to element 45 as "a host computer" (col. 10, line 13) and to element 21 as "a main frame" (col. 8, line 9). Neither of these elements mentioned by Maeng resemble a handler as described in the instant specification. See page 11, first paragraph, for example, which states that "handler 304 preferably comprises an enclosed space that IC's are disposed within while tests are performed by the first and second testers 336/308." Therefore, Applicant respectfully submits that the rejection is improper and should be withdrawn. Claims 2-11 are patentable over Maeng by virtue of their dependence from a patentable base claim.

Claim 3 includes the features of test heads and load boards. Maeng does not disclose test heads and load boards. The Examiner relies on Maeng's apparatus 100 as the claimed test head, and relies on Maeng's chamber 32 as a load board. Chamber 32 clearly is not a load board (see page 5 of the instant specification, last paragraph, where it is stated that a load board "includes a of [sic] plurality of sockets 252 that are adapted to supported and make electrical contact to IC devices under test."

Claim 4 includes first and second devices adapted to move ICs to load boards. The Examiner points to Maeng's rails 38 or transferring member 40 as

the first and second devices. As indicated above, Maeng does not disclose a load board as that term is used herein. Therefore, neither rails 38 or transferring member 40 move ICs to a test head. Note also that transferring member 40 only transfers IC from process to process, not within a process (col. 8, lines 45-47).

Claim 5 includes the feature wherein the first tester is a low cost tester and the second tester is a high cost tester. Applicant can find no reference in Maeng to the costs of the various components shown in Figures 4 and 5. The Examiner only points to one of Maeng's apparatuses 100 as low cost and another as high cost without specifying where Maeng discloses such features.

Claim 8 includes the feature wherein "the first test procedure comprises prescreening tests, wherein the second test procedure comprises detailed functional tests." Maeng does not teach tests of different detail occurring in a particular order. At col. 10, 5-11, for example, Maeng states that the DC/burn-in test could occur second or last in the sequence (thus distinguishing it from a "prescreening test").

Claim 10 includes the feature wherein "first IC's that fail the first test procedures are not moved to the second tester for testing with the second test procedure." The Examiner relies on Maeng's sorter 51 as supplying this claimed feature. However, sorter 51 is positioned at the output of the third of Maeng's apparatuses 100. It therefore cannot prevent or otherwise determine the movement of sorted IC's from the first tester to the second tester in Maeng's system.

Claim 12 includes the feature of first and second testers coupled to a single handler. As argued above with regard to Claim 1, the rejection of Claim 12 is improper since Maeng does not teach a handler as that term is used in the instant specification. Therefore, Applicant respectfully requests that the rejections be withdrawn. Claims 13-18 are patentable over Maeng by virtue of their dependence from a patentable base claim.

Claim 15 includes the feature wherein "the first test procedure comprises testing IC's with prescreening tests, wherein the second test procedure comprises testing IC's with detailed functional tests." As argued above with

respect to Claim 8, Maeng does not teach tests of different detail occurring in a particular order.

Claim 17 includes the feature of not moving first IC's that fail the first test procedures to the second tester for testing with the second test procedure. As argued above with respect to Claim 10, Maeng's sorter 51 is positioned at the output of the third of Maeng's apparatuses 100. It therefore cannot prevent or otherwise determine the movement of sorted IC's from the first tester to the second tester in Maeng's system.

Claim 19 includes the step of performing first and second test procedures within a single enclosed handler. The Examiner's error in relying on Maeng's host computer 45 and main frame 21 to fill the role of the claimed "single enclosed handler" is clear. None of Maeng's test procedures occur within an enclosed computer. Maeng's trays 10 do not enter the computer. Therefore, Applicant respectfully submits that the rejection is improper and should be withdrawn.

Claim 20 includes the feature wherein "the first tester comprises a low cost tester, wherein the first test procedure comprises testing IC's with prescreening tests, wherein the second tester comprises a high cost tester, and wherein the second test procedure comprises testing IC's with detailed functional tests." As argued above with regard to Claims 5 and 8, Applicant can find no reference in Maeng to the costs of the various components shown in Figures 4 and 5. Also, Maeng does not teach tests of different detail occurring in a particular order. Therefore, Applicant respectfully submits that the rejection is improper and should be withdrawn.

Applicant respectfully requests reconsideration and withdrawal of the rejections and allowance of Claims 1-20. If the Examiner has any questions or other correspondence regarding this application, Applicant requests that the Examiner contact Applicant's attorney at the below listed telephone number and address.

Respectfully submitted,

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